



Cylindrical Metrology Probes

These tips are widely used in Veeco's X-3D and Insight - Systems.

Typical application of CDP - Tips are depth measurements. The CDP200A is widely used for scanner orthogonality calibration

To compensate for tip mount tilt the cylindrical probe tips can also be fabricated in a tilted version. Typical off the shelf tilt angle is 3°.

Tip Apex Specifications

Type	Tip width [nm]	Effective length [nm]
CDP 200 A	130 - 270	500 - 700
CDP 55 L	40 - 55	800 - 1000
CD 55 A	40 - 55	500 - 700
CDP 35	25 - 35	*)
CDP 25	15 - 25	*)
CDP 15	< 15	> 150 *)

*) Please note required length in your quotation request.

The CDP probes are also available with carbon coating for improved wear characteristics.

Please inquire for tilt compensated CDP probes.

Please let us know if you have special needs for tip width or effective length.

Each probe is individually quality inspected by imaging in a SEM.
A certificate with measurement values and images will be provided (a sample can be found in the document section).

CDP probes are shipped in packs of 5 tips.

Probe tip, cantilever, and holder chip consist of single crystal silicon.

Each chip is uniquely numbered.

All cantilevers are shipped with Al-reflex coating.

Each probe is individually quality inspected by imaging in a SEM.
A certificate with measurement values and images will be provided (a sample can be found in the document section).

General Specifications

Cantilever dimensions	length = 125 (\pm 15) μ m width = 35 (\pm 3) μ m
Typical stiffness:	40 N/m
Resonant frequency:	300 (\pm 95) kHz
Holder chip dimensions	length = 3.40 mm width = 1.55 mm thickness = 0.32 mm

CDP-Auswahl:	200A,55L,55A,35,25,15,please choose
CDR-SEM:	with SEM,no SEM